Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/679,948	TANAKA, SHUICHI
Examiner	**Art Unit**
Paul D. Kim	3729

SEARCHED			
Class	Subclass	Date	Examiner
29	592.1 602.1 831 835 846 854 871-873	6/7/2006	PK
349	149-152		
445	24		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text Search EAST/NPL (IEEE)	6/7/2006	PK